# **IGBT - Short-Circuit Rated**

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Non–Punch Through (NPT) Trench construction, and provides superior performance in demanding switching applications. Offering both low on state voltage and minimal switching loss, the IGBT is well suited for motor drive control and other hard switching applications. Incorporated into the device is a rugged co–packaged reverse recovery diode with a low forward voltage.

#### Features

- Low Saturation Voltage Resulting in Low Conduction Loss
- Low Switching Loss in Higher Frequency Applications
- Soft Fast Reverse Recovery Diode
- 5 µs Short Circuit Capability
- Excellent Current versus Package Size Performance Density
- This is a Pb–Free Device

#### **Typical Applications**

- White Goods Appliance Motor Control
- General Purpose Inverter
- AC and DC Motor Control

#### **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector-emitter voltage	V <sub>CES</sub>	600	V
Collector current @ Tc = 25°C @ Tc = 100°C	I <sub>C</sub>	30 15	A
Pulsed collector current, $T_{\text{pulse}}$ limited by $T_{\text{Jmax}}$	I <sub>CM</sub>	120	A
Diode forward current @ Tc = 25°C @ Tc = 100°C	l <sub>F</sub>	30 15	A
Diode pulsed current, $T_{\text{pulse}}$ limited by $T_{\text{Jmax}}$	I <sub>FM</sub>	120	A
Gate-emitter voltage	$V_{GE}$	±20	V
Power dissipation @ Tc = 25°C @ Tc = 100°C	P <sub>D</sub>	117 47	W
Short circuit withstand time $V_{GE}$ = 15 V, $V_{CE}$ = 400 V, $T_J \leq +150^{\circ}C$	t <sub>SC</sub>	5	μs
Operating junction temperature range	ΤJ	–55 to +150	°C
Storage temperature range	T <sub>stg</sub>	–55 to +150	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T <sub>SLD</sub>	260	°C

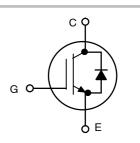
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

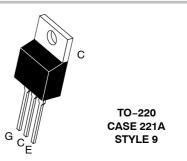


### **ON Semiconductor®**

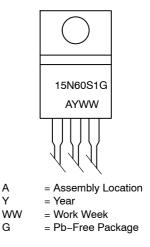
http://onsemi.com

15 A, 600 V V<sub>CEsat</sub> = 1.5 V





#### MARKING DIAGRAM



#### **ORDERING INFORMATION**

Device	Package	Shipping
NGTB15N60S1EG	TO-220 (Pb-Free)	50 Units / Rail

#### THERMAL CHARACTERISTICS

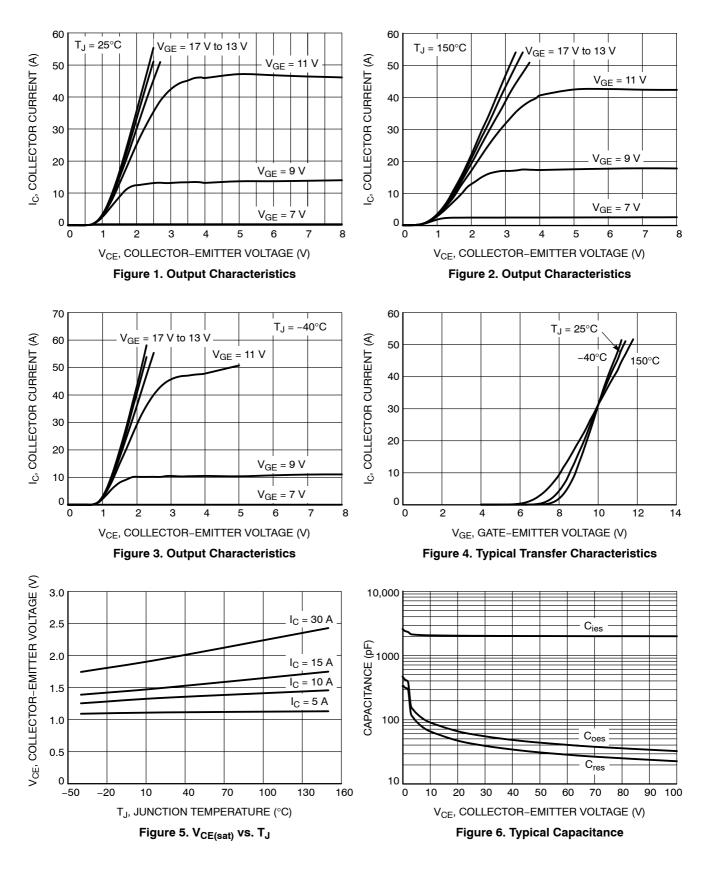
Rating	Symbol	Value	Unit
Thermal resistance junction to case, for IGBT	$R_{\theta JC}$	1.06	°C/W
Thermal resistance junction to case, for Diode	$R_{\theta JC}$	3.76	°C/W
Thermal resistance junction to ambient	$R_{ hetaJA}$	60	°C/W

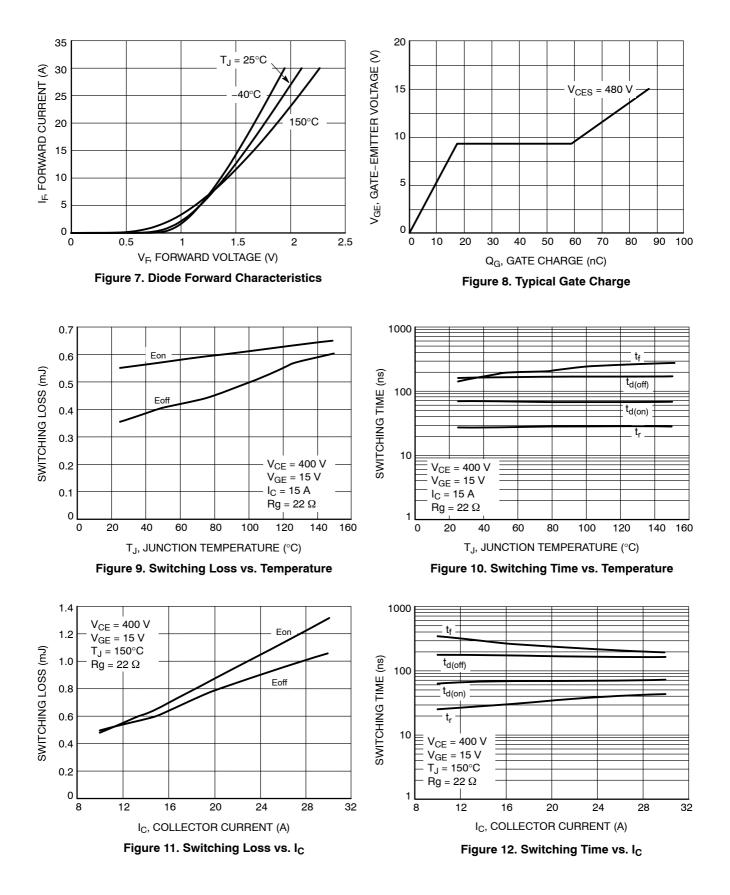
#### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

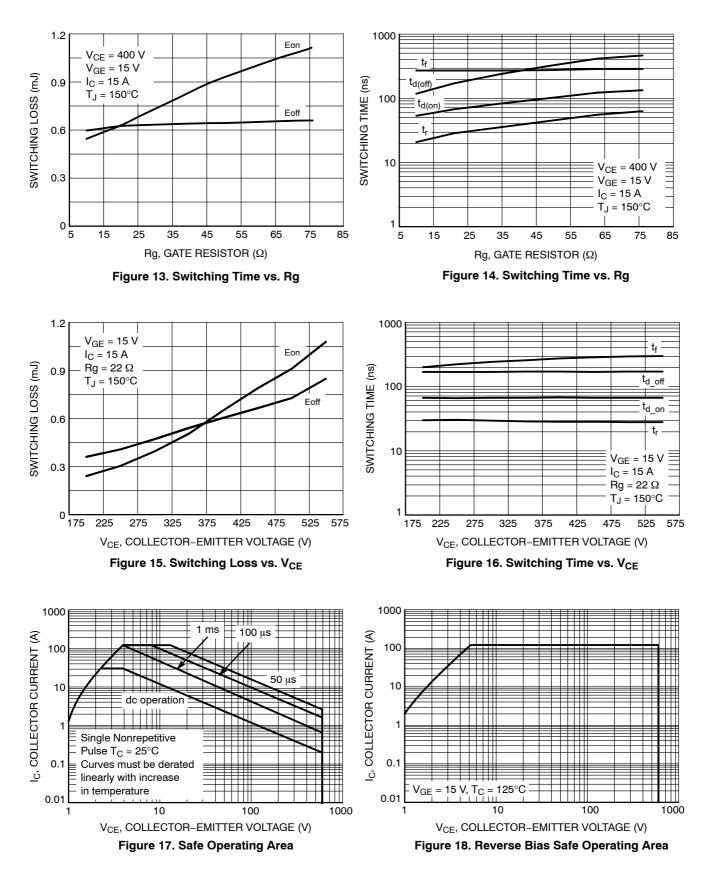
Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC		•				
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE}$ = 0 V, I <sub>C</sub> = 500 $\mu$ A		600	-	-	V
Collector-emitter saturation voltage	$V_{GE}$ = 15 V , $I_C$ = 15 A $V_{GE}$ = 15 V , $I_C$ = 15 A, $T_J$ = 150°C	V <sub>CEsat</sub>	1.3 1.55	1.5 1.75	1.7 1.95	V
Gate-emitter threshold voltage	$V_{GE}$ = $V_{CE}$ , $I_{C}$ = 250 $\mu A$	V <sub>GE(th)</sub>	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate-emitter short-circuited	$V_{GE}$ = 0 V, $V_{CE}$ = 600 V $V_{GE}$ = 0 V, $V_{CE}$ = 600 V, $T_{J}$ = 150°C	I <sub>CES</sub>	-	10 -	_ 200	μA
Gate leakage current, collector-emitter short-circuited	$V_{GE}$ = 20 V, $V_{CE}$ = 0 V	I <sub>GES</sub>	-	-	100	nA
Forward Transconductance	$V_{CE}$ = 20 V, $I_{C}$ = 15 A	9fs	-	10.1	-	S
DYNAMIC CHARACTERISTIC						
Input capacitance		Cies	-	1950	-	
Output capacitance	$V_{CE}$ = 20 V, $V_{GE}$ = 0 V, f = 1 MHz	C <sub>oes</sub>	-	70	-	pF
Reverse transfer capacitance		C <sub>res</sub>	-	42	-	
Gate charge total		Qg	-	88	-	
Gate to emitter charge	$V_{CE}$ = 480 V, I <sub>C</sub> = 15 A, V <sub>GE</sub> = 15 V	Q <sub>ge</sub>	-	16	-	nC
Gate to collector charge		Q <sub>gc</sub>	-	42	-	
SWITCHING CHARACTERISTIC , INDUCTIVE	LOAD	•				
Turn-on delay time		t <sub>d(on)</sub>	-	65	-	
Rise time		t <sub>r</sub>	-	28	-	ns
Turn-off delay time	$T_J = 25^{\circ}C$	t <sub>d(off)</sub>	-	170	-	
Fall time	$V_{CC} = 400 \text{ V}, \text{ I}_{C} = 15 \text{ A}$	t <sub>f</sub>	-	140	-	
Turn-on switching loss	R <sub>g</sub> = 22 Ω V <sub>GE</sub> = 0 V / 15 V	Eon	-	0.550	-	
Turn-off switching loss		E <sub>off</sub>	_	0.350	-	mJ
Total switching loss		E <sub>ts</sub>	_	0.900	-	
Turn-on delay time		t <sub>d(on)</sub>	_	65	-	
Rise time		t <sub>r</sub>	-	28	-	
Turn-off delay time	T <sub>J</sub> = 150°C	t <sub>d(off)</sub>	-	180	-	ns
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 15 \text{ A}$	t <sub>f</sub>	-	260	-	
Turn–on switching loss	$R_g = 22 \Omega$ $V_{GE} = 0 V / 15 V$	Eon	-	0.650	-	
Turn–off switching loss		E <sub>off</sub>	-	0.600	-	mJ
Total switching loss		E <sub>ts</sub>	-	1.250	-	
DIODE CHARACTERISTIC		I				
Forward voltage	V <sub>GE</sub> = 0 V, I <sub>F</sub> = 15 A V <sub>GE</sub> = 0 V, I <sub>F</sub> = 15 A, T <sub>J</sub> = 150°C	V <sub>F</sub>	-	1.65 1.75	1.85 -	V
		1				

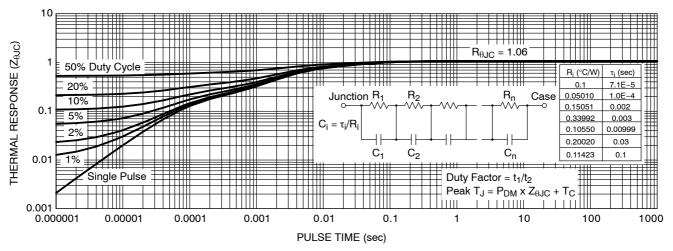
## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit	
DIODE CHARACTERISTIC							
Reverse recovery time	T <sub>J</sub> = 25°C I <sub>F</sub> = 15 A, V <sub>R</sub> = 200 V di <sub>F</sub> /dt = 200 A/μs	t <sub>rr</sub>	-	270	-	ns	
Reverse recovery charge		Q <sub>rr</sub>	-	350	-	nc	
Reverse recovery current		I <sub>rrm</sub>	-	5	-	А	
Reverse recovery time	T <sub>J</sub> = 125°C I <sub>F</sub> = 15 A, V <sub>R</sub> = 200 V di <sub>F</sub> /dt = 200 A/μs	t <sub>rr</sub>	-	350	-	ns	
Reverse recovery charge		Q <sub>rr</sub>	-	1000	-	nc	
Reverse recovery current		I <sub>rrm</sub>	-	7.5	-	А	











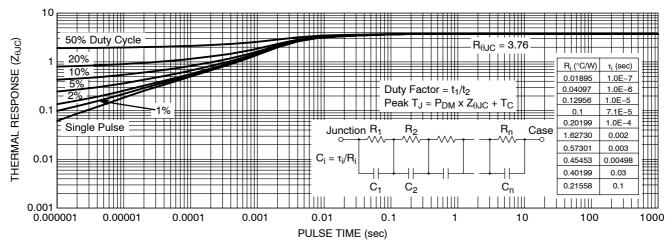


Figure 20. Diode Transient Thermal Impedance

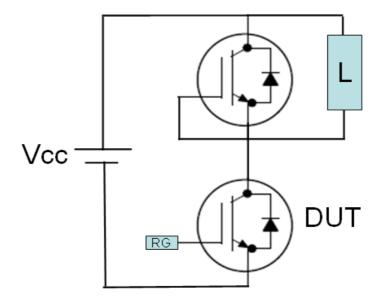
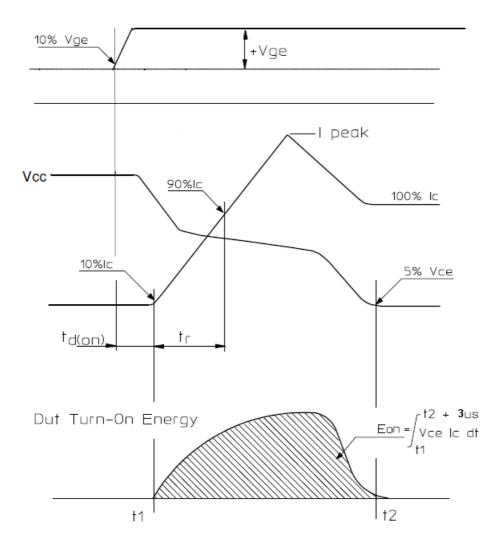


Figure 21. Test Circuit for Switching Characteristics





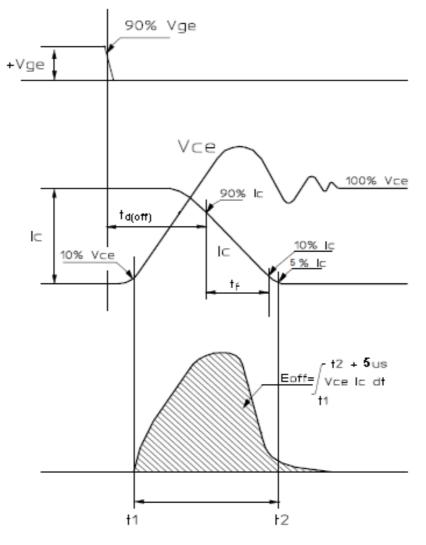
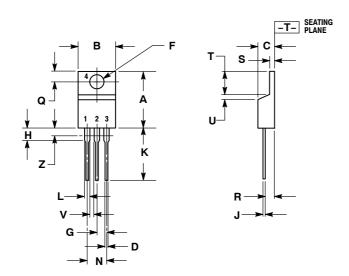


Figure 23. Definition of Turn Off Waveform

#### PACKAGE DIMENSIONS

TO-220 CASE 221A-09 ISSUE AG



NOTES:

 DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH. 3. DIMENSION Z DEFINES A ZONE WHERE AL

 DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.570	0.620	14.48	15.75
В	0.380	0.405	9.66	10.28
C	0.160	0.190	4.07	4.82
D	0.025	0.036	0.64	0.91
F	0.142	0.161	3.61	4.09
G	0.095	0.105	2.42	2.66
Н	0.110	0.161	2.80	4.10
J	0.014	0.025	0.36	0.64
K	0.500	0.562	12.70	14.27
L	0.045	0.060	1.15	1.52
Ν	0.190	0.210	4.83	5.33
Q	0.100	0.120	2.54	3.04
R	0.080	0.110	2.04	2.79
S	0.045	0.055	1.15	1.39
Т	0.235	0.255	5.97	6.47
υ	0.000	0.050	0.00	1.27
۷	0.045		1.15	
Ζ		0.080		2.04

STYLE 9: PIN 1. GATE

2. COLLECTOR

3. EMITTER 4 COLLECTOR

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